



MS RCE  
PATENT  
8053-1008

IN THE U.S. PATENT AND TRADEMARK OFFICE

In re application of: Yuichi NAITOU et al.  
Conf.: 7712  
Appl. No.: 09/981,390  
Group: 2881  
Filed: October 18, 2001  
Examiner: Phillip Johnston  
Title: SCANNING PROBE MICROSCOPE WITH PROBE  
FORMED BY SINGLE CONDUCTIVE MATERIAL

AMENDMENT

Assistant Commissioner for Patents  
Alexandria, VA 22313-1450

December 5, 2003

Sir:

In response to the Office Action mailed August 5, 2003,  
please amend the above-identified application as follows:

**Amendments to the Claims** are reflected in the listing  
of claims which begins on page 2 of this paper.

**Remarks/Arguments** begin on page 21 of this paper.

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